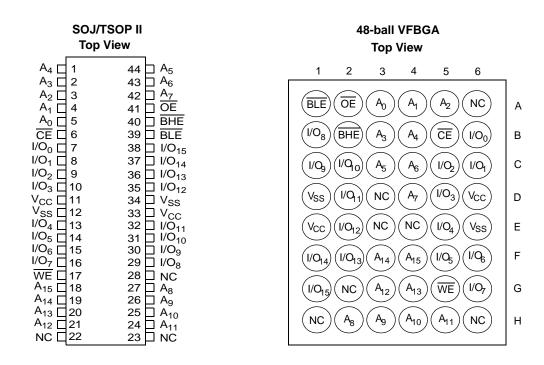


#### **Selection Guide**

	-10 (Industrial/Automotive-A)	Unit
Maximum access time	10	ns
Maximum operating current	60	mA
Maximum CMOS standby current	3	mA

### Pin Configuration[1]



<sup>1.</sup> NC pins are not connected on the die.



### **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage temperature ......-65 °C to +150 °C Ambient temperature with power applied .......55 °C to +125 °C Supply voltage on  $\rm V_{CC}$  to Relative  $\rm GND^{[2]}\,...-0.3~V$  to +4.6  $\rm V$ DC Voltage applied to outputs in high-Z  $\rm State^{[2]}$  .......-0.3 V to  $\rm V_{CC}\text{+}0.3~V$ DC input voltage<sup>[2]</sup>.....-0.3 V to V<sub>CC</sub>+0.3 V

Current into outputs (LOW)	20 mA
Static discharge voltage(per MIL-STD-883, method 3015)	> 2001 V
Latch-up current	>200 mA

#### **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>	Speed
Industrial	−40 °C to +85°C	$3.3 \text{ V} \pm 0.3 \text{ V}$	10 ns
Automotive-A	−40 °C to +85°C		10 ns

### DC Electrical Characteristics Over the Operating Range

Doromotor	Description	Test Conditions		–10 (Ind	I/Auto-A)	Unit
Parameter	Description	lest Conditions		Min.	Max.	Onit
V <sub>OH</sub>	Output HIGH voltage	$V_{CC} = Min., I_{OH} = -4.0 \text{ mA}$	2.4		V	
V <sub>OL</sub>	Output LOW voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA			0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage <sup>[2]</sup>			-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_1 \le V_{CC}$		-1	+1	μΑ
I <sub>OZ</sub>	Output leakage current	$GND \le V_1 \le V_{CC}$ , Output Disabl	ed	-1	+1	μА
I <sub>CC</sub>	V <sub>CC</sub> operating	V <sub>CC</sub> = Max.,	100 MHz		60	mA
	supply current	$I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$	83 MHz		55	mA
		I IWAX "RC	66 MHz		45	mA
			40 MHz		30	mA
I <sub>SB1</sub>	Automatic CE Power-Down Current —TTL Inputs	$\begin{aligned} &\text{Max. V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}} \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{f} = \text{f}_{\text{MAX}} \end{aligned}$			10	mA
I <sub>SB2</sub>	Automatic CE Power-Down Current —CMOS Inputs	Max. $V_{CC}$ , $\overline{CE} \ge V_{CC} - 0.3 \text{ V}$ , $V_{IN} \ge V_{CC} - 0.3 \text{ V}$ or $V_{IN} \le 0.3 \text{ V}$	V, f = 0		3	mA

### Capacitance<sup>[3]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = 3.3$ V	8	pF
C <sub>OUT</sub>	Output capacitance		8	pF

#### Thermal Resistance[3]

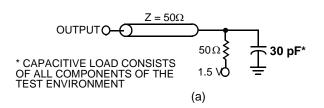
Parameter	Description	Test Conditions	SOJ	TSOP II	VFBGA	Unit
$\Theta_{JA}$		Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	59.52	53.91	36	°C/W
$\Theta_{\sf JC}$	Thermal resistance (Junction to Case)		36.75	21.24	9	°C/W

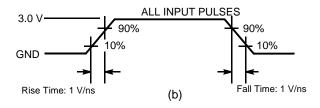
<sup>2.</sup> V<sub>IL</sub> (min.) = -2.0 V and V<sub>IH</sub>(max) = V<sub>CC</sub> + 1 V for pulse durations of less than 5 ns.

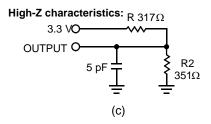
3. Tested initially and after any design or process changes that may affect these parameters.



#### AC Test Loads and Waveforms[4]







#### Note

AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).



#### Switching Characteristics Over the Operating Range<sup>[5]</sup>

		-10 (Ind	I/Auto-A)	
Parameter	Description	Min.	Max.	Unit
Read Cycle		<u>'</u>	•	
t <sub>power</sub> <sup>[6]</sup>	V <sub>CC</sub> (typical) to the first access	100		μS
t <sub>RC</sub>	Read cycle time	10		ns
t <sub>AA</sub>	Address to data valid		10	ns
t <sub>OHA</sub>	Data hold from address change	3		ns
t <sub>ACE</sub>	CE LOW to data valid		10	ns
t <sub>DOE</sub>	OE LOW to data valid		5	ns
t <sub>LZOE</sub>	OE LOW to low-Z <sup>[8]</sup>	0		ns
t <sub>HZOE</sub>	OE HIGH to high-Z <sup>[7, 8]</sup>		5	ns
t <sub>LZCE</sub>	CE LOW to low-Z <sup>[8]</sup>	3		ns
HZCE CE HIGH to high-Z <sup>[7, 8]</sup>			5	ns
t <sub>PU</sub> <sup>[9]</sup>	CE LOW to power-up	0		ns
t <sub>PD</sub> <sup>[9]</sup>	CE HIGH to power-down		10	ns
t <sub>DBE</sub>	Byte Enable to data valid		5	ns
t <sub>LZBE</sub>	Byte Enable to low-Z	0		ns
t <sub>HZBE</sub>	Byte Disable to high-Z		6	ns
Write Cycle <sup>[10]</sup>			•	
t <sub>WC</sub>	Write cycle time	10		ns
t <sub>SCE</sub>	CE LOW to write end	8		ns
t <sub>AW</sub>	Address set-up to write end	8		ns
t <sub>HA</sub>	Address hold from write end	0		ns
t <sub>SA</sub>	Address set-up to write start	0		ns
t <sub>PWE</sub>	WE pulse width	7		ns
t <sub>SD</sub>	Data set-up to write end	5		ns
t <sub>HD</sub>	Data hold from write end	0		ns
t <sub>LZWE</sub>	WE HIGH to low-Z <sup>[8]</sup>	3		ns
t <sub>HZWE</sub>	WE LOW to high-Z <sup>[7, 8]</sup>		5	ns
t <sub>BW</sub>	Byte enable to end of write	7		ns

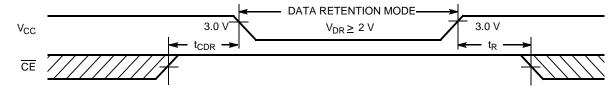
- Notes
   Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
   tpower gives the minimum amount of time that the power supply should be at typical V<sub>CC</sub> values until the first memory access can be performed.
   th\_IZOE, th\_IZDE, th\_IZDE, th\_IZDE, and th\_IZWE are specified with a load capacitance of 5 pF as in (c) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.
   At any given temperature and voltage condition, th\_IZCE is less than th\_IZCE, th\_IZOE, and th\_IZWE is less than th\_IZCE, and the IZCE, a



### Data Retention Characteristics Over the Operating Range

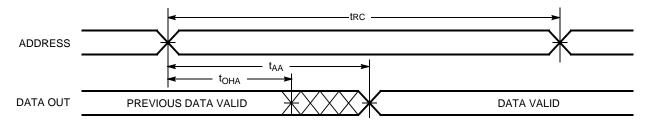
Parameter	Description	Conditions	Min.	Max.	Unit
$V_{DR}$	V <sub>CC</sub> for data retention		2		V
I <sub>CCDR</sub>	Data retention current	$ \begin{vmatrix} V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V}, \\ V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V} \end{vmatrix}                                  $		3	mA
t <sub>CDR</sub> <sup>[3]</sup>	Chip deselect to data retention time		0		ns
t <sub>R</sub> <sup>[11]</sup>	Operation recovery time		t <sub>RC</sub>		ns

#### **Data Retention Waveform**

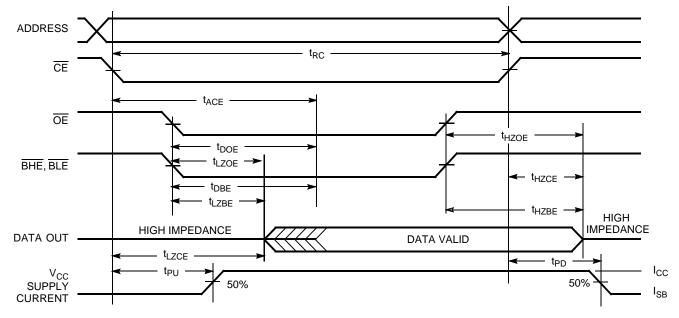


### **Switching Waveforms**

### Read Cycle No. 1 (Address Transition Controlled)[12, 13]



### Read Cycle No. 2 (OE Controlled)[13, 14]



- 11. Full device operation requires lin<u>ear V<sub>CC</sub> ramp</u> from V<sub>DR</sub> to V<sub>CC(min.)</sub> ≥ 50 μs or stable at V<sub>CC(min.)</sub> ≥ 50 μs.

  12. Device is continuously selected. OE, CE, BHE and/or BLE = V<sub>IL</sub>.

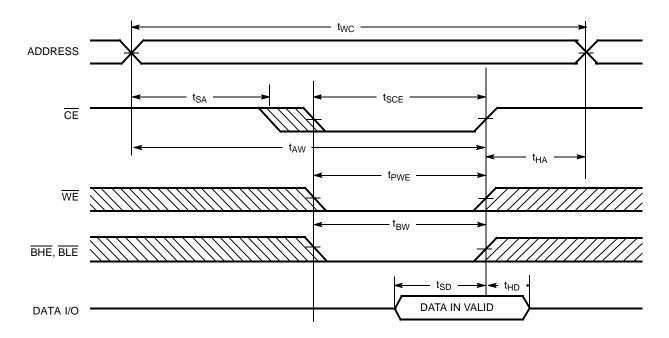
  13. WE is HIGH for Read cycle.

  14. Address valid prior to or coincident with CE transition LOW.

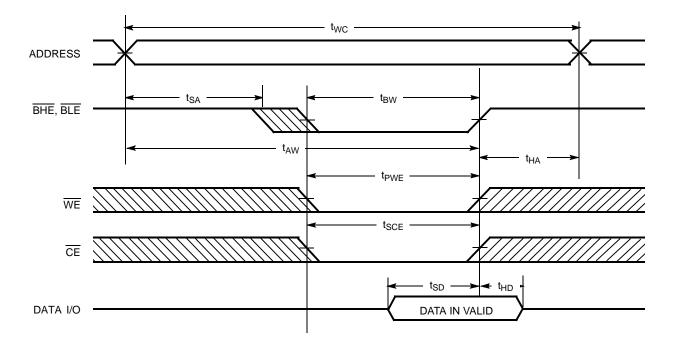


### **Switching Waveforms** (continued)

### Write Cycle No. 1 (CE Controlled)[15, 16]



# Write Cycle No. 2 (BLE or BHE Controlled)



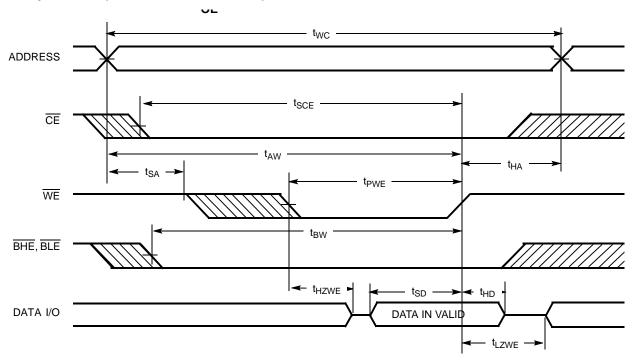
<sup>15.</sup> Data I/O is high impedance if  $\overline{OE}$  or  $\overline{BHE}$  and/or  $\overline{BLE} = V_{IH}$ .

16. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state.



# Switching Waveforms (continued)

## Write Cycle No. 3 (WE Controlled, OE LOW)



### **Truth Table**

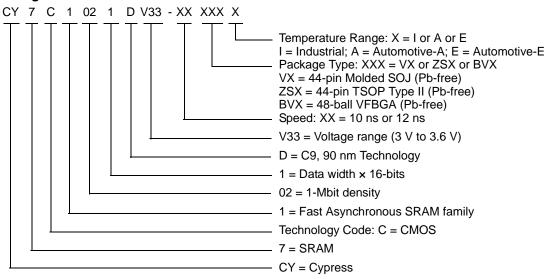
CE	OE	WE	BLE	BHE	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> –I/O <sub>15</sub>	Mode	Power
Н	Х	Х	Χ	Х	High-Z	High-Z	Power-down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read – All bits	Active (I <sub>CC</sub> )
			L	Н	Data Out	High-Z	Read – Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High-Z	Data Out	Read – Upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write – All bits	Active (I <sub>CC</sub> )
			L	Н	Data In	High-Z	Write – Lower bits only	Active (I <sub>CC</sub> )
			Н	L	High-Z	Data In	Write – Upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	X	Х	High-Z	High-Z	Selected, outputs disabled	Active (I <sub>CC</sub> )
L	Х	Х	Н	Н	High-Z	High-Z	Selected, outputs disabled	Active (I <sub>CC</sub> )



#### **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1021DV33-10VXI	51-85082	44-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1021DV33-10ZSXI	51-85087	44-pin TSOP Type II (Pb-free)	
	CY7C1021DV33-10BVXI	51-85150	48-ball VFBGA (Pb-free)	
10	CY7C1021DV33-10ZSXA	51-85087	44-pin TSOP Type II (Pb-free)	Automotive-A

#### **Ordering Code Definitions**

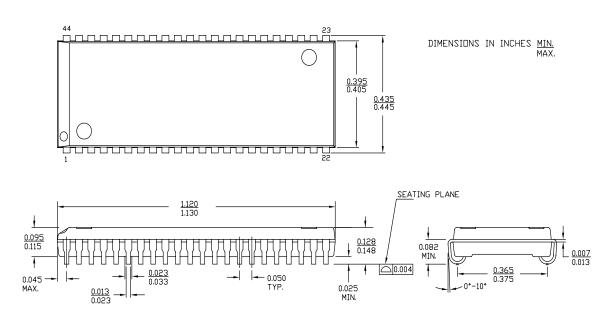


 $\label{thm:please contact your local Cypress sales representative for availability of these parts. \\$ 



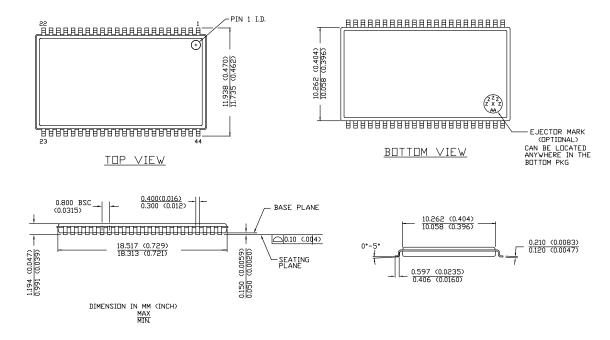
### **Package Diagrams**

Figure 1. 44-pin (400-Mil) Molded SOJ (51-85082)



51-85082 \*D

Figure 2. 44-pin Thin Small Outline Package Type II (51-85087)

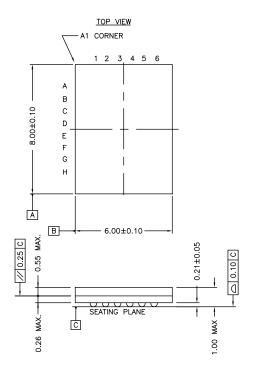


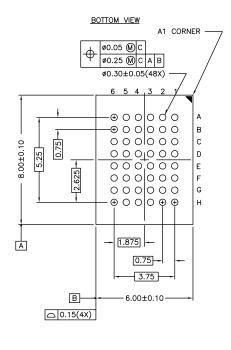
51-85087 \*D



### Package Diagrams (continued)

#### Figure 3. 48-ball VFBGA (6 x 8 x 1 mm) (51-85150)





51-85150 \*G



# **Document History Page**

REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change		
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP		
*A	233693	See ECN	RKF	DC parameters are modified as per Eros (Spec # 01-02165). Pb-free Offering In Ordering Information		
*B	263769	See ECN	RKF	Added Data Retention Characteristics table Added T <sub>power</sub> Spec in Switching Characteristics table Shaded Ordering Information		
*C	307601	See ECN	RKF	Reduced Speed bins to -8 and -10 ns		
*D	520652	See ECN	VKN	Converted from Preliminary to Final Removed Commercial Operating range Removed 8 ns speed bin Added I <sub>CC</sub> values for the frequencies 83MHz, 66MHz and 40MHz Added Automotive Information Updated Thermal Resistance table Updated Ordering Information Table Changed Overshoot spec from V <sub>CC</sub> +2 V to V <sub>CC</sub> +1 V in footnote #4		
*E	2898399	03/24/2010	AJU	Updated Package Diagrams		
*F	3109897	12/14/2010	AJU	Added Ordering Code Definitions. Updated Package Diagrams.		
*G	3421856	10/25/2011	TAVA	Template Update Updated Features, Selection Guide, Operating Range, DC Electrical Chara teristics Over the Operating Range, Switching Characteristics Over the Operating Range <sup>[5]</sup> , Data Retention Characteristics Over the Operating Range Switching Waveforms, and Ordering Information Updated Package Diagrams		



#### Sales, Solutions, and Legal Information

#### Worldwide Sales and Design Support

Cypress maintains a worldwide network of offices, solution centers, manufacturer's representatives, and distributors. To find the office closest to you, visit us at cypress.com/sales.

#### **Products**

Automotive cypress.com/go/automotive Clocks & Buffers cypress.com/go/clocks Interface cypress.com/go/interface Lighting & Power Control cypress.com/go/powerpsoc cypress.com/go/plc Memory

cypress.com/go/memory Optical & Image Sensing cypress.com/go/image **PSoC** cypress.com/go/psoc Touch Sensing cypress.com/go/touch **USB** Controllers cypress.com/go/USB Wireless/RF cypress.com/go/wireless

#### **PSoC Solutions**

psoc.cypress.com/solutions PSoC 1 | PSoC 3 | PSoC 5

All products and company names mentioned in this document are the trademarks of their respective holders.

© Cypress Semiconductor Corporation, 2008-2011. The information contained herein is subject to change without notice. Cypress Semiconductor Corporation assumes no responsibility for the use of any circuitry other than circuitry embodied in a Cypress product. Nor does it convey or imply any license under patent or other rights. Cypress products are not warranted nor intended to be used for medical, life support, life saving, critical control or safety applications, unless pursuant to an express written agreement with Cypress. Furthermore, Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress products in life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Any Source Code (software and/or firmware) is owned by Cypress Semiconductor Corporation (Cypress) and is protected by and subject to worldwide patent protection (United States and foreign), United States copyright laws and international treaty provisions. Cypress hereby grants to licensee a personal, non-exclusive, non-transferable license to copy, use, modify, create derivative works of, and compile the Cypress Source Code and derivative works for the sole purpose of creating custom software and or firmware in support of licensee product to be used only in conjunction with a Cypress integrated circuit as specified in the applicable agreement. Any reproduction, modification, translation, compilation, or representation of this Source Code except as specified above is prohibited without the express written permission of Cypress.

Disclaimer: CYPRESS MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARD TO THIS MATERIAL, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Cypress reserves the right to make changes without further notice to the materials described herein. Cypress does not assume any liability arising out of the application or use of any product or circuit described herein. Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress' product in a life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Use may be limited by and subject to the applicable Cypress software license agreement.

Document #: 38-05460 Rev. \*G Revised October 25, 2011 Page 13 of 13

# **Mouser Electronics**

**Authorized Distributor** 

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

# Cypress Semiconductor:

<u>CY7C1021DV33-10BVXI</u> <u>CY7C1021DV33-10BVXIT</u> <u>CY7C1021DV33-10VXI</u> <u>CY7C1021DV33-10VXI</u> <u>CY7C1021DV33-10ZSXI</u> <u>CY7C1021DV33-10ZSXI</u> <u>CY7C1021DV33-10ZSXA</u>